
**Metallic and other inorganic
coatings — Simultaneous thickness
and electrode potential determination
of individual layers in multilayer
nickel deposits (STEP test)**

*Revêtements métalliques et autres revêtements inorganiques —
Détermination simultanée de l'épaisseur et du potentiel d'électrode
de couches individuelles dans des dépôts de nickel multicouches
(essai STEP)*

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Contents

Page

Foreword	iv
Introduction	v
1 Scope	1
2 Normative references	1
3 Terms and definitions	1
4 Test equipment	1
4.1 Construction of the measuring cell.....	1
4.2 Composition of the test solution.....	2
5 Requirements	3
6 Sampling	3
7 Factors influencing measurement accuracy	3
7.1 Electrolyte.....	3
7.2 Conditioning.....	3
7.3 Ni deposits.....	3
7.4 Surface cleanliness.....	3
7.5 Measurement area and contact pressure.....	3
7.6 Electrical contact.....	4
7.7 Complete dissolution.....	4
8 Procedure	4
8.1 General.....	4
8.2 Measurement.....	4
8.3 Evaluation.....	5
9 Measurement uncertainty	8
10 Test report	9
Annex A (informative) Precision data obtained by a round robin test	10
Bibliography	11

Foreword

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This document was prepared by the European Committee for Standardization (CEN) (as EN 16866:2017) and was adopted, without modification, by Technical Committee ISO/TC 107, *Metallic and other inorganic coatings*.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.

Introduction

The abbreviated term “STEP” represents “Simultaneous Thickness and Electrode Potential determination”.

The STEP test can be used to measure, in one single operating step, the parameters (thickness of the individual nickel layers and the potential differences among them) relevant for the course of corrosion in a multilayer nickel system. Provided suitable instruments are applied, it can also be used to document them.

The test is a modification of the well-known coulometric method for the measurement of the coating thickness. This method takes advantage of the fact that, following the anodic dissolution of a nickel coating, a potential jump takes place of which the magnitude can be measured against a reference electrode.

Although, nowadays, the STEP test has been incorporated into a number of company standards, particularly in the automobile industry, there are currently no uniform and generally acknowledged potential difference values available. At present, values between 80 mV and 150 mV are assumed for double nickel layers, with the semi-bright nickel layer always being nobler than the bright one.

Likewise, no obligatory numerical values are available, currently, regarding the potential difference between bright nickel layers and existing special nickel layers (e.g. in the case of micro-porous chromium plating). According to the current practical experience, the potential difference is larger than approximately 20 mV, with the bright nickel layer always having to be less noble than the special nickel layer.

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